



MICROCHIP

QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN #: RMES-10TYKT692

Date:
July 02, 2019

Qualification of NSEB as a new assembly site for selected products available in 8L DFN (4x4x0.9mm) package.



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose	Qualification of NSEB as a new assembly site for selected products available in 8L DFN (4x4x0.9mm) package.
CCB No.	3674
CN	ES291544
QUAL ID	Q19062 Rev. A
MP CODE	VGGA14M8XV21
Part No.	MCP8063-E/MDVAO
Bonding No.	BDM-002022 Rev. A
<u>Package</u>	
Type	8L DFN
Package size	4x4x0.9 mm
Die thickness	8 mils
Die size	61.7 x 84.3 mils
<u>Lead Frame</u>	
Paddle size	114 x 146 mils
Material	C194
Surface	Ag no lead and Ag on PAD
Process	Etched
Lead Lock	Yes
Part Number	FR0225
<u>Material</u>	
Epoxy	8600
Wire	Au wire
Mold Compound	G700LTD
Plating Composition	Matte Tin



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
NSEB195100067.000	TC03915327695.100	1912HTU
NSEB195100068.000	TC03915327695.100	1912HU0
NSEB195100069.000	TC03915327695.100	1912HU8

Result

Pass Fail _____

8L DFN 4x4x0.9 mm assembled by NSEB pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard / Method	Qty. (Acc.)	Def/S S	Result	Remarks
Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020E)	IPC/JEDEC C J-STD-020E	135	0/135	Pass	

Precondition Prior Perform Reliability Tests (At MSL Level 1)	Electrical Test :+25°C and 125°C System: ETS300	JESD22-A113	693(0)	693	Pass	Good Devices
	Bake 150°C, 24 hrs System: CHINEE			693		
	85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			693		
	Electrical Test :+25°C and 125°C System: ETS300			0/693		

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System : TABAI ESPEC TSA-70H	JESD22- A104		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +125°C System: ETS300		231(0)	0/231	Pass	77 units / lot
	Bond Strength: Wire Pull (> 8.00 grams)		15 (0)	0/15	Pass	
	Bond Shear (>20.00 grams)		15 (0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: ETS300		231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 3.3 Volts System: HAST 6000X	JESD22- A110		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C and 125°C System: ETS300		231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 500 hrs System: SHEL LAB	JESD22-A103		45		45 units
	Electrical Test :+25°C and 125°C System: ETS300		45(0)	0/45	Pass	
Solderability Temp 245°C	Steam Aging: Temp 93°C,8Hrs System: SAS-3000 Solder Dipping: Solder Temp.245°C Solder material:Pb Free Sn 95.5Ag3.9 Cu0.6 System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22 (0)	22 22 0/22	Pass	
Physical Dimensions	Physical Dimension, 10 units from 1 lot	JESD22-B100/B108	30(0) Units	0/30	Pass	
Bond Strength Data Assembly	Wire Pull (> 8.00 grams)	M2011	30 (0) Wires	0/30	Pass	
	Bond Shear (>20.00 grams)	JESD22-B116	30 (0) bonds	0/30	Pass	